

Agilent 720 ICP-OES

The Agilent 720 with axially- viewed plasma provides exceptionally low detection limit performance. Featuring CCI, the Agilent 720 is suited to **environmental, food, agriculture** and **industrial** applications.



Features Agilent 720 ICP-OES

- **Reliable Agilent 720 ICP-OES**
Continuous wavelength coverage provides the ability to select multiple wavelengths for a given element, thereby extending dynamic range and avoiding interferences, giving you maximum confidence in your results.
- **Productive Agilent 720 ICP-OES**
One view, one step measurement of major, minor, and trace elements, plus the fastest warm-up, increases through put and productivity.
- **Robust Agilent 720 ICP-OES**
Exceptionally robust plasma ensures reliable and reproducible results, even with the most complex matrices.
- **Cost-effective Agilent 720 ICP-OES**
With a sealed CCD detector that requires no purging, a compact optical system, and an efficient RF system that sustains an analytical plasma at lower argon flows, the Agilent 720 lower gas usage and operating costs.
- **Flexible Agilent 720 ICP-OES**
Choice of optimized axial configurations to suit your application needs.
- **Intuitive Agilent 720 ICP-OES**
Software features providing automation and ease-of- use.

Agilent 720 ICP-OES — productivity with extended dynamic range

Agilent's 720 horizontally-oriented, axially-viewed plasma provides excellent sensitivity for trace-level determinations and the flexibility to handle major levels. The robust plasma is able to analyze a wide variety of sample matrices while still delivering the best detection limits. Agilent's unique MultiCal feature extends the linear range of an analyte from parts-per-billion to percentage levels. Unlike dual-view systems, the Agilent 720 ICP-OES provides this linear dynamic range without having to analyze the sample twice.

The 720 ICP-OES is ideal for the analysis of waters and wastes, soils and sediments, foods, beverages and agricultural samples, and is capable of measuring elements from trace to major levels simultaneously, with one plasma view.